REMARKS

The above amendments are presented in order to place the application into a format consistent with U.S. practice. A markup sheet is provided at the end of this document to illustrate the changes made for the Examiner.

Respectfully submitted,

James H.

Walters, Reg. No.

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DELLETT AND WALTERS

Suite 1101

310 S.W. Fourth Avenue

Portland, Oregon 97204 US

(503) 224-0115

DOCKET: A-413

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and a process in which repeating pattern data of gratingshaped grooves and strips, which have different pitches, are written in juxtaposition with each other.

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Brief Description of the Drawings

Fig. 1 is a diagram for describing the principle that the connection error at the joint between patterns is minimized by the present invention.

Figs. 2(a) and 2(b) comprise diagrams

Fig. 2 is a diagram showing an electron beam writing

method used in the method of producing a phase mask, and also showing a section of the phase mask.

Fig. 3 is a diagram showing the way in which a pattern having a varying pitch is written by connecting

together patterns having different pitches.

Figs. 4(a) through 4(h) are views

Fig. 4 is a sectional view showing steps of an embodiment of the phase mask producing method according to the present invention.

Figs. 5(a) through 5(c) comprise diagrams

Fig. 5 is a diagram for describing optical fiber

processing and a phase mask used therefor.

Fig. 6 is a diagram schematically showing the way in which a phase mask pattern is written with an electron beam by using an electron beam writing system.

Fig. 7 is a diagram showing the way in which a plurality of patterns having different pitches are written by multiple writing operations carried out in opposite directions.

Fig. 8 is a diagram showing the way in which a plurality of patterns having different pitches are written